



INTELLECTUAL PROPERTY
402-391-4448

JAMES D. WELCH
ATTORNEY AT LAW
PROFESSIONAL ENGINEER

2877
1 328 PINEHURST AVE.
OMAHA, NEBRASKA 8124

November 23, 2003

Commissioner for Patents
Box: 1450
Alexandria, VA 22313-1450

RE: APPLICATION OF TIWALD TITLED: METHOD FOR EVALUATING COMPLEX
REFRACTIVE INDICIES UTILIZING IR RANGE ELLIPSOMETRY;
SERIAL NO. 09/888,598;
FILING DATE: 06/25/01;
ART UNIT: 2877;
EXAMINER: SMITH, Z.

Dear Sir;

I am in receipt of an Action dated 10/06/03 regarding the identified Application. The Examiner has Allowed the Claims but for Formalities. Amended Claims are presented herein which it is believed overcome the problems.

IN THE ABSTRACT

Please cancel the Original Abstract and enter the accompanying New Abstract.

ABSTRACT

A method of evaluating mathematical model parameters which describe directions and magnitudes of real and imaginary components of orthogonally related Kramers-Kroenig consistent

dielectric functions or complex refractive indicies in an optically thick material system which presents with an optical axis oriented either in-plane or out-of-plane, with respect to an alignment surface of the optically thick material system. The method is particularly applicable to investigation of optically thick material systems which are uniaxial or biaxial using IR range wavelengths.